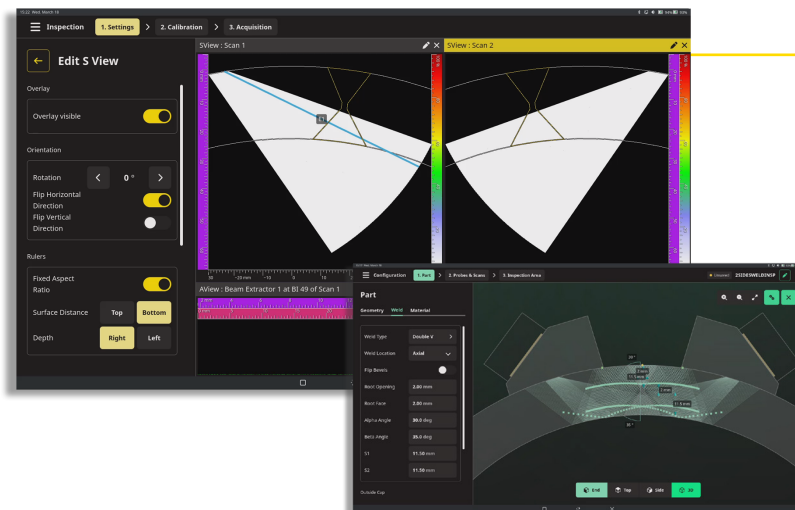


Fast in Any Application

Advanced Imaging and Inspection Technologies

The XEO ecosystem always leverages inspection across all geometric situations. Adding up meaningful scans creates an intuitive environment and solves your most pressing inspection challenges.



PHASED ARRAY

The instrument is capable of true geometry rendering with sectorial and linear scanning.

This allows a **comprehensive data reviewing**.

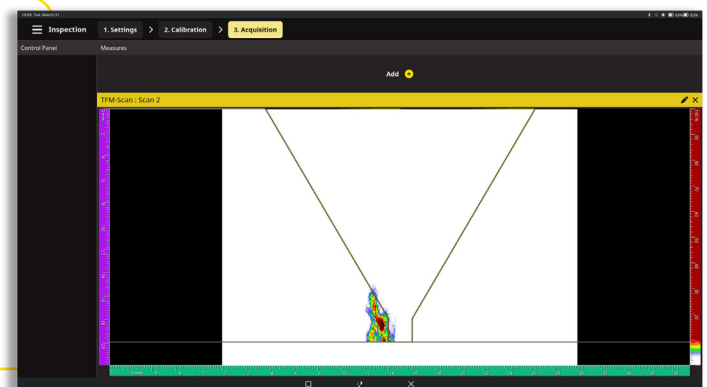
With our **3D ray tracing**, validate your configuration to ensure maximum coverage of your inspections.

TFM/TFMI

Get fast and live images from one or many of the 16 propagation modes available on flat and curved parts.

The defect profile fidelity is key to characterisation.

With up to 4 megapixels per image, you will never miss a thing.



MULTIPLE TECHNIQUES

Using complementary techniques assures a **higher detection rate** of every defect.

With XEO, Phased array, TFM, TOFD; all techniques can be used in the same configuration.

For a complete inspection in only one scan, take advantage of the mini-dock flexibility.

